

Si4835DY

P-Channel Logic Level PowerTrench® MOSFET

General Description

This P-Channel Logic Level MOSFET is produced using Fairchild Semiconductor's advanced PowerTrench process that has been especially tailored to minimize on-state resistance and yet maintain superior switching performance.

These devices are well suited for low voltage and battery powered applications where low in-line power loss and fast switching are required.

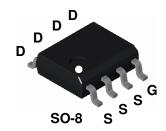
Applications

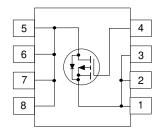
- · Battery protection
- · Load switch
- Motor drives

Features

• -8.8 A, -30 V.
$$R_{DS(ON)}=0.020~\Omega$$
 @ $V_{GS}=-10~V$
$$R_{DS(ON)}=0.035~\Omega$$
 @ $V_{GS}=-4.5~V$

- Extended V_{GSS} range ($\pm 25 \text{V}$) for battery applications.
- Low gate charge (19nC typical).
- · Fast switching speed.
- • High performance trench technology for extremely low $R_{\scriptscriptstyle DS(ON)}.$
- High power and current handling capability.





Absolute Maximum Ratings T_A = 25°C unless otherwise noted

| Symbol | Parameter | | Ratings | Units |
|-----------------------------------|--|-----------|-------------|-------|
| V _{DSS} | Drain-Source Voltage | | -30 | V |
| V _{GSS} | Gate-Source Voltage | | ±25 | V |
| I _D | Drain Current - Continuous | (Note 1a) | -8.8 | A |
| | - Pulsed | | -50 | |
| P _D | Power Dissipation for Single Operation | (Note 1a) | 2.5 | W |
| | | (Note 1b) | 1.2 | |
| | | (Note 1c) | 1 | |
| T _J , T _{stg} | Operating and Storage Junction Temperature | Range | -55 to +150 | °C |

Thermal Characteristics

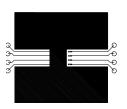
| $R_{\theta JA}$ | Thermal Resistance, Junction-to-Ambient | (Note 1a) | 50 | °C/W |
|-----------------|---|-----------|----|------|
| $R_{\theta JC}$ | Thermal Resistance, Junction-to-Case | (Note 1) | 25 | °C/W |

Package Outlines and Ordering Information

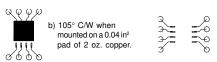
| Device Marking | Device | Reel Size | Tape Width | Quantity |
|----------------|----------|-----------|------------|------------|
| 4835 | Si4835DY | 13" | 12mm | 2500 units |
| | • | | | • |

| Symbol | Parameter | Test Conditions | Min | Тур | Max | Units |
|--|---|--|-----|-------------------------|-------------------------|-------|
| Off Char | acteristics | | | l | I | I |
| BV _{DSS} | Drain-Source Breakdown Voltage | $V_{GS} = 0 \text{ V}, I_{D} = -250 \mu\text{A}$ | -30 | | | V |
| ∆BV _{DSS} ∆T, _J | Breakdown Voltage Temperature Coefficient | I_D = -250 μ A,Referenced to 25°C | | -24 | | mV/°C |
| DSS | Zero Gate Voltage Drain Current | $V_{DS} = -24 \text{ V}, V_{GS} = 0 \text{ V}$ | | | -1 | μΑ |
| GSSF | Gate-Body Leakage Current, Forward | $V_{GS} = 25 \text{ V}, V_{DS} = 0 \text{ V}$ | | | 100 | nA |
| GSSR | Gate-Body Leakage Current, Reverse | $V_{GS} = -25 \text{ V}, V_{DS} = 0 \text{ V}$ | | | -100 | nA |
| On Char | acteristics (Note 2) | | | | | |
| V _{GS(th)} | Gate Threshold Voltage | $V_{DS} = V_{GS}, I_{D} = -250 \mu\text{A}$ | -1 | -2 | -3 | V |
| $\Delta V_{GS(th)}$ ΔT_J | Gate Threshold Voltage Temperature Coefficient | I_D = -250 μ A,Referenced to 25°C | | 5 | | mV/°C |
| R _{DS(on)} | Static Drain-Source On-Resistance | $V_{GS} = -10 \text{ V}, I_D = -8.8 \text{ A}$ $V_{GS} = -10 \text{ V}, I_D = -8.8 \text{ A}, T_J = 125^{\circ}\text{C}$ $V_{GS} = -4.5 \text{ V}, I_D = -6.7 \text{ A}$ | | 0.015 0.023 0.026 | 0.020 0.032 0.035 | Ω |
| D(on) | On-State Drain Current | $V_{GS} = -10 \text{ V}, V_{DS} = -5 \text{ V}$ | -25 | | | Α |
|]FS | Forward Transconductance | $V_{DS} = -10 \text{ V}, I_{D} = -8.8 \text{ A}$ | | 20 | | S |
| Dynamic | Characteristics | | | | | |
| C _{iss} | Input Capacitance | $V_{DS} = -15 \ V, V_{GS} = 0 \ V,$ | | 1680 | | pF |
| Coss | Output Capacitance | f = 1.0 MHz | | 545 | | pF |
| C _{rss} | Reverse Transfer Capacitance | | | 220 | | pF |
| Switchir | ng Characteristics (Note 2) | | | ı | 1 | I |
| d(on) | Turn-On Delay Time | $V_{DD} = -15 \text{ V}, I_{D} = -1 \text{ A},$ | | 12 | 22 | ns |
| r | Turn-On Rise Time | $V_{GS} = -10 \text{ V}, R_{GEN} = 6 \Omega$ | | 15 | 27 | ns |
| d(off) | Turn-Off Delay Time | | | 55 | 90 | ns |
| f | Turn-Off Fall Time | | | 23 | 37 | ns |
| Q_g | Total Gate Charge | $V_{DS} = -10 \text{ V}, I_{D} = -8.8 \text{ A},$ | | 19 | 27 | nC |
| Q _{qs} | Gate-Source Charge | $V_{GS} = -5 V$, | | 6.8 | | nC |
| Q_{gd} | Gate-Drain Charge | | | 7.2 | | nC |
| Drain-Sc | ource Diode Characteristics a | nd Maximum Ratings | | • | • | • |
| l _s | Maximum Continuous Drain-Source Did | · · | | | -2.1 | Α |
| V _{SD} | Drain-Source Diode Forward Voltage | V _{GS} = 0 V, I _S = -2.1 A (Note 2) | | -0.52 | -1.2 | V |

1: R_{BJA} is the sum of the junction-to-case and case-to-ambient resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. $\rm R_{\theta JC}$ is guaranteed by design while $\rm R_{\theta JA}$ is determined by the user's board design.



a) 50° C/W when mounted on a 1 in² pad of 2 oz. copper.





c) 125° C/W on a minimum mounting pad of 2 oz. copper.

Scale 1 : 1 on letter size paper

2: Pulse Test: Pulse Width $\leq 300~\mu\text{s},~\text{Duty Cycle} \leq 2.0\%$

Typical Characteristics

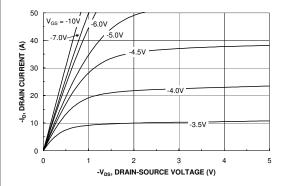


Figure 1. On-Region Characteristics

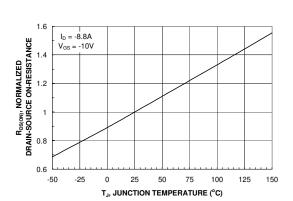


Figure 3. On-Resistance Variation with Temperature

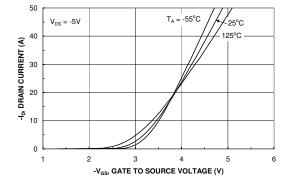


Figure 5. Transfer Characteristics

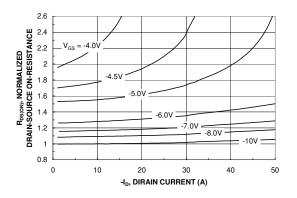


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage

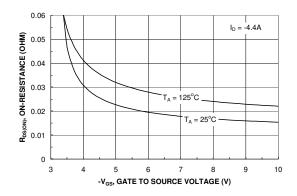


Figure 4. On-Resistance Variation with Gate-to-Source Voltage

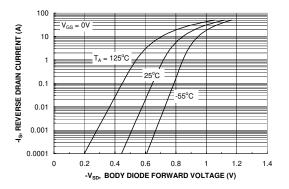
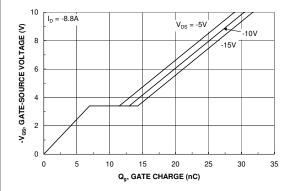


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature

Typical Characteristics (continued)



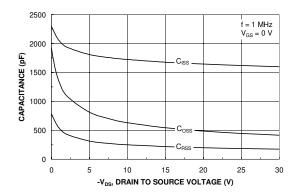
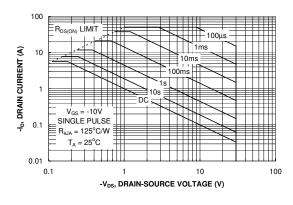


Figure 7. Gate-Charge Characteristics





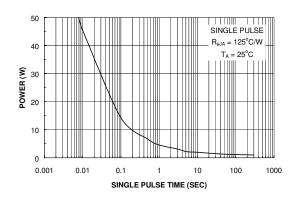


Figure 9. Maximum Safe Operating Area

Figure 10. Single Pulse Maximum Power Dissipation

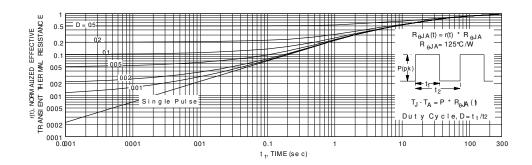


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1c. Transient themal response will change depending on the circuit board design.

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